ABSTRACT OF THE DISCLOSURE

A resist pattern for lift-off is formed on a first film composed of one or more layers deposited on a substrate. The first film is patterned by dry-etching using the resist mask. Subsequently, a second film is pattern as a deposited with presence of the resist pattern on the first film. Then, the resist pattern for lift-off is removed for conducting lift-off. Subsequently, the resulting substrate is In the etching, the substrate is dry-etched using etched. etching particles which are oriented at an incident angle set in a range of 60° to 90° relative to the normal direction of the substrate.